## 2022 IEEE/ACM International Conference on Automation of Software Test (AST 2022)

Pittsburgh, Pennsylvania, USA 17-18 May 2022



IEEE Catalog Number: CFP2215D-POD ISBN: 978-1-6654-5205-2

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IEEE Catalog Number: CFP2215D-POD CFP2215D-POD 978-1-6654-5205-2 ISBN (Print-On-Demand): ISBN (Online): 978-1-4503-9286-0

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# 3rd ACM/IEEE International Conference on Automation of Software Test AST 2022

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